

IGBT for Automotive Applications

650 V, 30 A

AFGB30T65RQDN

Using novel field stop IGBT technology, **onsemi**'s new series of FS4 IGBTs offer the optimum performance for automotive applications. This technology is Short circuit rated and offers high figure of merit with low conduction and switching losses.

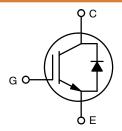
Features

- Maximum Junction Temperature: $T_J = 175^{\circ}C$
- Positive Temperature Coefficient for Easy Parallel Operation
- High Current Capability
- Low Saturation Voltage: $V_{CE(Sat)} = 1.58 \text{ V (Typ.)}$ @ $I_C = 30 \text{ A}$
- 100% of the Parts Tested for ILM (Note 2)
- High Input Impedance
- Fast Switching
- Tightened Parameter Distribution
- This Device is Pb-Free and RoHS Compliant

Typical Applications

- E-compressor for HEV/EV
- PTC Heater for HEV/EV

BV _{CES}	V _{CE(sat)} TYP	I _C
650 V	1.58 V	30 A





MARKING DIAGRAM



&Y = Logo

&Z = Assembly Plant Code &3 = 3-Digit Date Code

&K = 2-Digit Lot Traceability Code

AFGB30T65RQDN = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping [†]
AFGB30T65RQDN	D2PAK (TO-263)	800 Units / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Value	Unit
Collector to Emitter Voltage	V _{CES}	650	V
Gate to Emitter Voltage Transient Gate to Emitter Voltage $T_{pulse} = 5 \ \mu s, \ D < 0.10$	V _{GES}	±20 ±30	V
Collector Current (Note 1) $@T_C = 25^{\circ}C$ $@T_C = 100^{\circ}C$	I _C	68 30	A
Pulsed Collector Current (Note 2)	I _{LM}	120	Α
Pulsed Collector Current (Note 3)	I _{CM}	120	Α
Diode Forward Current (Note 1) $@T_C = 25^{\circ}C$ $@T_C = 100^{\circ}C$	I _F	68 30	А
Pulsed Diode Maximum Forward Current	I _{FM}	120	Α
Non-Repetitive Forward Surge Current (Half-Sine Pulse, tp = 8.3 ms , $T_C = 25^{\circ}\text{C}$) (Half-Sine Pulse, tp = 8.3 ms , $T_C = 150^{\circ}\text{C}$)	I _{F,} SM	140 100	А
Short Circuit Withstand Time V_{GE} = 15 V, V_{CC} = 400 V, T_{C} = 150°C	T _{SC}	5	μs
Maximum Power Dissipation $@T_C = 25^{\circ}C$ $@T_C = 100^{\circ}C$	P _D	235.48 117.74	W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	- 55 to +175	°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	T _L	265	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Value limited by bond wire.

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Min	Тур	Max	Unit
Thermal Resistance Junction-to-Case, for IGBT	$R_{ heta JC}$	-	0.49	0.64	°C/W
Thermal Resistance Junction-to-Case, for Diode	$R_{ heta JC}$	_	0.97	1.26	
Thermal Resistance Junction-to-Ambient	$R_{ heta JA}$	-	-	40	

^{2.} V_{CC} = 400 V, V_{GE} = 15 V, I_{C} = 90 A, R_{G} = 100 Ω , Inductive Load, 100% Tested. 3. Repetitive rating: pulse width limited by max. Junction temperature.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise stated)

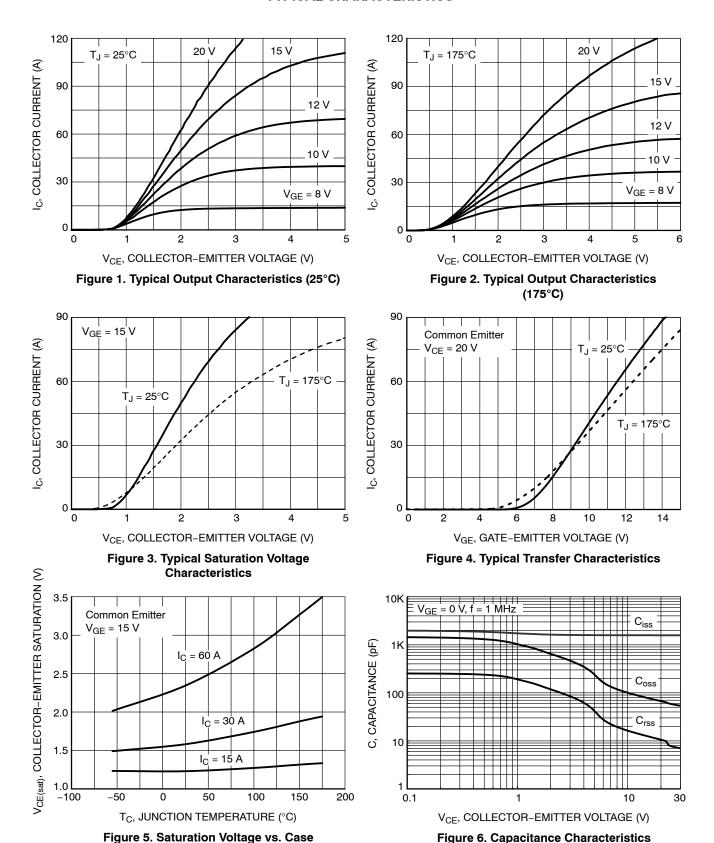
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	-	•		-		_
Collector-to-Emitter Breakdown Voltage, Gate-Emitter Short-Circuited	BV _{CES}	V _{GE} = 0 V, I _C = 1 mA	650	-	-	V
Temperature Coefficient of Breakdown Voltage	$\Delta BV_CES / \Delta T_J$	V _{GE} = 0 V, I _C = 1 mA	-	0.61	-	V/°C
Collector–Emitter Cut–Off Current, Gate–Emitter Short–Circuited	I _{CES}	$V_{CE} = V_{CES}, V_{GE} = 0 V$	-	-	30	μΑ
Gate Leakage Current, Collector–Emitter Short–Circuited	I _{GES}	V _{GE} = V _{GES} , V _{CE} = 0 V	-	-	±400	nA
ON CHARACTERISTICS	I					
Gate-Emitter Threshold Voltage	V _{GE(th)}	$V_{GE} = V_{CE}$, $I_C = 30 \text{ mA}$	4.30	5.30	6.30	V
Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _C = 30 A, V _{GE} = 15 V, T _J = 25°C	-	1.58	1.82	V
		I _C = 30 A, V _{GE} = 15 V, T _J = 175°C	-	1.94	-	V
DYNAMIC CHARACTERISTICS	•	•	•	•		
Input Capacitance	C _{ies}	V _{CE} = 30 V, V _{GE} = 0 V, f = 1 MHz	_	1580	_	pF
Output Capacitance	C _{oes}	1	_	54	_	
Reverse Transfer Capacitance	C _{res}	1	_	7	-	
Gate Resistance	Rg	FREQ = 1 MHz	-	15	-	Ω
Gate Charge Total	Qg	V _{CE} = 400 V, I _C = 30 A, V _{GE} = 15 V	_	38	_	nC
Gate-Emitter Charge	Q _{ge}	1	_	13	-	
Gate-Collector Charge	Q _{gc}	1	_	11	-	
SWITCHING CHARACTERISTICS, INDUC	TIVE LOAD	•				
Turn-On Delay Time	t _{d(on)}	$T_J = 25^{\circ}C$, $V_{CC} = 400 \text{ V}$, $I_C = 15 \text{ A}$,	_	20	_	ns
Rise Time	t _r	$R_g = 2.5 \Omega$, $V_{GE} = 15 V$, Inductive Load	_	18	_	
Turn-Off Delay Time	t _{d(off)}	7	_	60	_	
Fall Time	t _f		_	92	_	
Turn-On Switching Loss	E _{on}		_	0.34	_	mJ
Turn-Off Switching Loss	E _{off}	7	_	0.32	_	
Total Switching Loss	E _{ts}	7	_	0.66	_	
Turn-On Delay Time	t _{d(on)}	$T_J = 25^{\circ}C$, $V_{CC} = 400 \text{ V}$, $I_C = 30 \text{ A}$,	_	18	_	ns
Rise Time	t _r	$R_g = 2.5 \Omega$, $V_{GE} = 15 V$, Inductive Load	_	37	_	
Turn-Off Delay Time	t _{d(off)}	1	_	48	_	
Fall Time	t _f	1	_	75	_	
Turn-On Switching Loss	E _{on}]	_	0.78	_	mJ
Turn-Off Switching Loss	E _{off}		-	0.56	-	
Total Switching Loss	E _{ts}		-	1.34	-	
Turn-On Delay Time	t _{d(on)}	$T_J = 175^{\circ}C$, $V_{CC} = 400 \text{ V}$, $I_C = 15 \text{ A}$,	-	20	ı	ns
Rise Time	t _r	$R_g = 2.5 \Omega$, $V_{GE} = 15 V$, Inductive Load	_	24	_	
Turn-Off Delay Time	t _{d(off)}]	_	76	_]
Fall Time	t _f]	_	184	_]
Turn-On Switching Loss	E _{on}]	_	0.48	_	mJ
Turn-Off Switching Loss	E _{off}		_	0.67	ı	
Total Switching Loss	E _{ts}	7	_	1.15	_]

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise stated) (continued)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS, IND	UCTIVE LOAD	•				
Turn-On Delay Time	t _{d(on)}	$T_J = 175^{\circ}C$, $V_{CC} = 400 \text{ V}$, $I_C = 30 \text{ A}$,	-	20	-	ns
Rise Time	t _r	$R_g = 2.5 \Omega$, $V_{GE} = 15 V$, Inductive Load	-	40	-	
Turn-Off Delay Time	t _{d(off)}		_	60	_	1
Fall Time	t _f		-	144	_	
Turn-On Switching Loss	E _{on}		-	1.10	_	mJ
Turn-Off Switching Loss	E _{off}		_	1.11	_	1
Total Switching Loss	E _{ts}		_	2.21	_	
DIODE CHARACTERISTICS						
Diode Forward Voltage	V _F	T _J = 25°C, I _F = 30 A	-	1.71	2.10	V
		T _J = 175°C, I _F = 30 A	-	1.76	-	
DIODE SWITCHING CHARACTERISTIC	C, INDUCTIVE L	OAD				
Reverse Recovery Energy	E _{REC}	T _J = 25°C, V _R = 400 V, - I _F = 15 A, di _F /dt = 1000 A/μs	-	36	-	μJ
Diode Reverse Recovery Time	T _{rr}		_	33	-	ns
Diode Reverse Recovery Charge	Q _{rr}		_	283	-	nC
Reverse Recovery Energy	E _{REC}	T _J = 25°C, V _R = 400 V,	-	56	-	μJ
Diode Reverse Recovery Time	T _{rr}	I _F = 30 A, di _F /dt = 1000 A/μs	-	44	-	ns
Diode Reverse Recovery Charge	Q _{rr}		-	408	-	nC
Reverse Recovery Energy	E _{REC}	$T_J = 175$ °C, $V_R = 400$ V, $I_F = 15$ A, $di_F/dt = 1000$ A/ μ s	-	154	-	μJ
Diode Reverse Recovery Time	T _{rr}		-	68	-	ns
Diode Reverse Recovery Charge	Q _{rr}		-	768	-	nC
Reverse Recovery Energy	E _{REC}	T _J = 175°C, V _R = 400 V,	-	224	-	μJ
Diode Reverse Recovery Time	T _{rr}	I _F = 30 A, di _F /dt = 1000 A/μs	_	91	-	ns
Diode Reverse Recovery Charge	Q _{rr}	7	_	1075	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS (Continued)

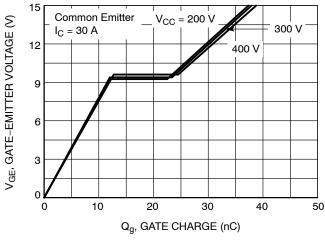


Figure 7. Gate Charge Characteristics

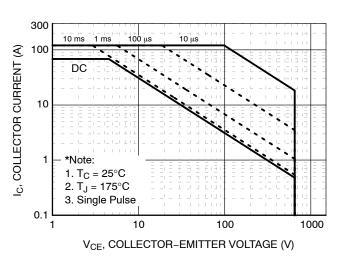


Figure 8. SOA Characteristics

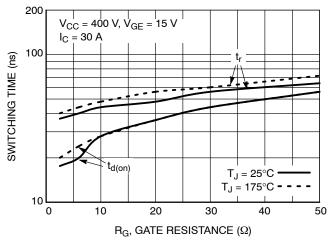


Figure 9. Turn-On Characteristics vs. Gate Resistance

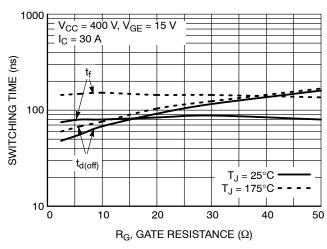


Figure 10. Turn-Off Characteristics vs. Gate Resistance

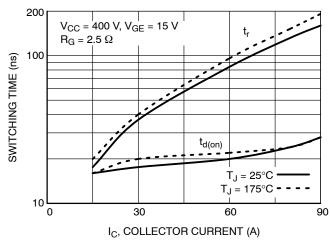


Figure 11. Turn-On Characteristics vs. Collector Current

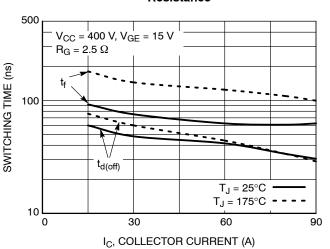


Figure 12. Turn-Off Characteristics vs.
Collector Current

TYPICAL CHARACTERISTICS (Continued)

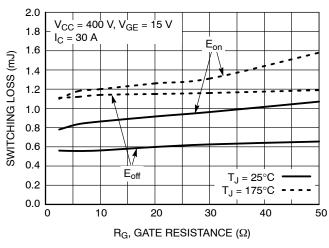


Figure 13. Switching Loss vs. Gate Resistance

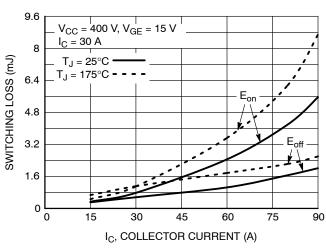


Figure 14. Switching Loss vs. Collector Current

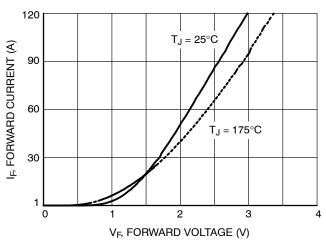


Figure 15. Forward Characteristics

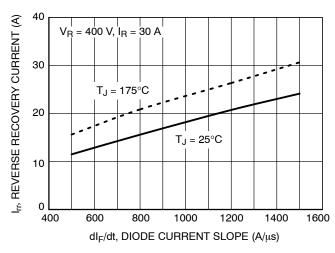


Figure 16. Reverse Recovery Current

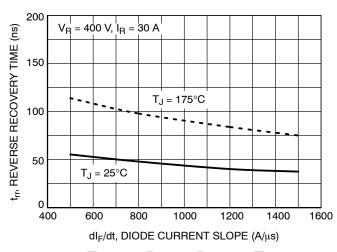


Figure 17. Reverse Recovery Time

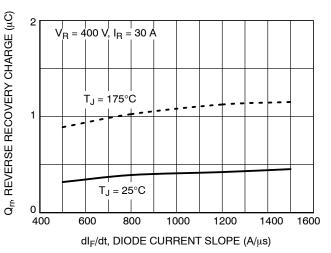


Figure 18. Stored Charge

TYPICAL CHARACTERISTICS (Continued)

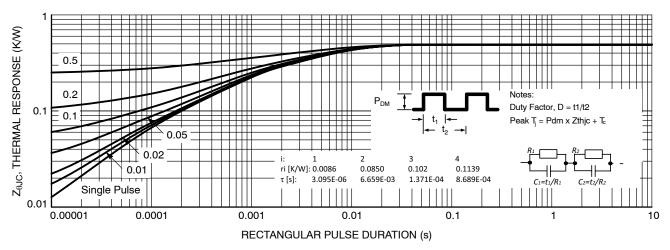


Figure 19. Transient Thermal Impedance of IGBT

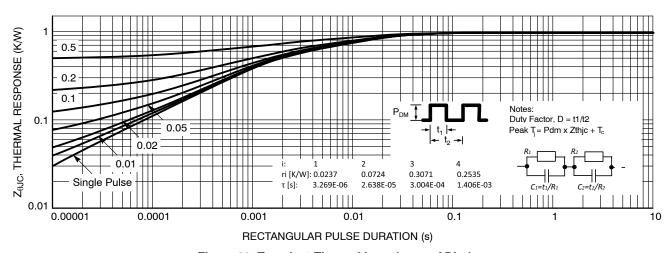


Figure 20. Transient Thermal Impedance of Diode

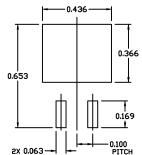




D²PAK-3 (TO-263, 3-LEAD) CASE 418AJ

ISSUE F

DATE 11 MAR 2021



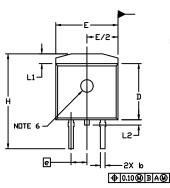
RECOMMENDED
MOUNTING FOOTPRINT

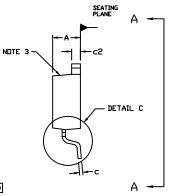
For additional information on our Pb-Free strategy and soldering details, please downloo the DN Seniconductor Soldering and Mounting

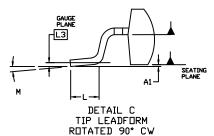
NOTES

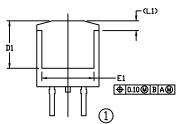
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: INCHES
- 3. CHAMFER OPTIONAL.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE DUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
- 6. OPTIONAL MOLD FEATURE.
- 7. ①,② ... OPTIONAL CONSTRUCTION FEATURE CALL DUTS.

	INCHES		MILLIMETERS	
DIM	MIN.	MAX.	MIN.	MAX.
A	0.160	0.190	4.06	4.83
A1	0.000	0.010	0.00	0.25
b	0.020	0.039	0.51	0.99
U	0.012	0.029	0.30	0.74
5	0.045	0.065	1.14	1.65
D	0.330	0.380	8.38	9.65
D1	0.260	i	6.60	
E	0.380	0.420	9.65	10.67
E1	0.245		6.22	
e	0.100 BSC		2.54 BSC	
Ξ	0.575	0.625	14.60	15.88
٦	0.070	0.110	1.78	2.79
L1		0.066		1.68
L2		0.070		1.78
L3	0.010 BSC		0.25 BSC	
М	0*	8*	0*	8*

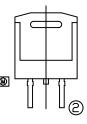


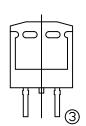


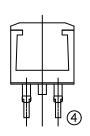




VIEW A-A







VIEW A-A

OPTIONAL CONSTRUCTIONS

GENERIC MARKING DIAGRAMS*

XXXXXX = Specific Device Code

A = Assembly Location
WL = Wafer Lot

Y = Year WW = Work Week W = Week Code (SSG)

M = Month Code (SSG)
G = Pb-Free Package
AKA = Polarity Indicator

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " •", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:

98AON56370E

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DESCRIPTION: D²P

D²PAK-3 (TO-263, 3-LEAD)

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